

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/092,159	GOOCH, MARK	
Examiner	Art Unit	•
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Class	Subclass	Date	Examiner
341	50,51	4/27/2006	Js
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370	209,211	4/27/2006	JS
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
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